

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

Am29821A/Am29823A/Am29825A Am29921A/Am29923A/Am29925A

High-Performance Bus Interface Registers

DISTINCTIVE CHARACTERISTICS

- High-speed parallel positive edge-triggered registers with D-type flip-flops
 - CP-Y tpD = 6 ns typical
- Buffered common Clock Enable (EN) and asynchronous Clear input (CLR)
- Three-state outputs glitch free during power-up and down. Outputs have Schottky clamp to ground
- IOL: 48 mA Commercial, 32 mA Military
- Higher speed, lower power versions of the Am29821, Am29823, & Am29825
- Am29900A DIP pinout option reduces lead inductance on V_{CC} and GND pins

GENERAL DESCRIPTION

The Am29821A, Am29823A, and Am29825A Buffered Registers are designed to eliminate the extra devices required to buffer stand alone registers and to provide extra data width for address/data paths or buses carrying parity. The Am29800A registers are produced with AMD's exclusive IMOX* bipolar process, and feature typical propagation delays of 6 ns, as well as high-capacitive drive capability.

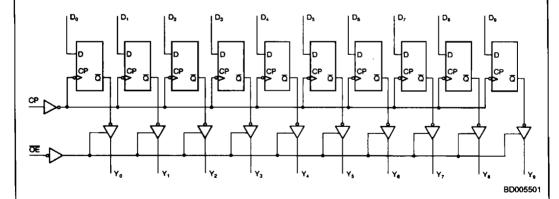
The Am29821A is a buffered, 10-bit version of the popular '374/'534 functions. The Am29823A is a 9-bit wide buffered register with Clock Enable (EN) and Clear (CLR)—ideal for parity bus interfacing in high-performance microprogrammed systems. The Am29825A, an 8-bit buffered

register, has all the 9-bit controls plus multiple enables $(\overline{OE}_1, \overline{OE}_2, \overline{OE}_3)$ to allow multi-user control of the interface; e.g., \overline{CS} , DMA, and RD/ \overline{WR} . The device is ideal for use as an output port requiring high |OL/OH|.

The Am29800A registers are available in the standard package options: DIPs, PLCCs, LCCs, SOICs, and Flatpacks. In addition, a DIP pinout option, featuring center V_{CC} and GND pins, reduces the lead inductance of the V_{CC} and GND pins. The ordering part numbers for registers with this pinout are the Am29921A, Am29923A, and Am29925A; their pinouts are shown later in this data sheet.

BLOCK DIAGRAMS**

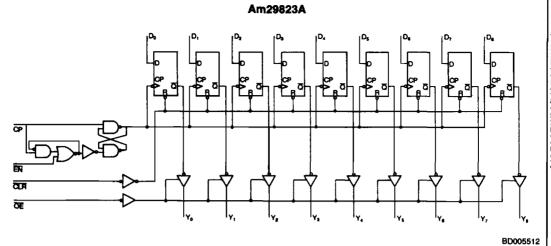
Am29821A



Publication # Rev. Amendment
07138 C /0
Issue Date: January 1988

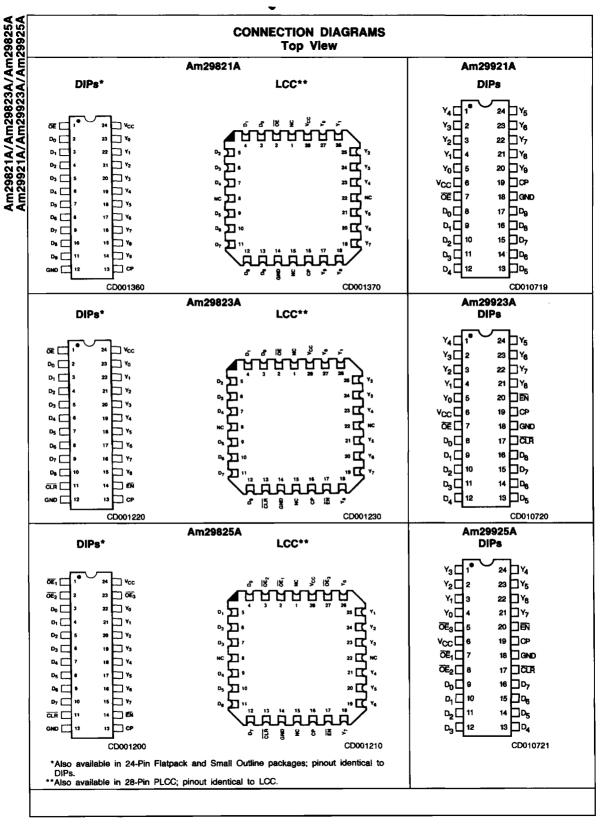
^{*1}MOX is a trademark of Advanced Micro Devices, Inc.
**See following page for additional Block Diagrams.

BD005522



BLOCK DIAGRAMS (Cont'd.)

Am29825A



FUNCTION TABLES (Cont'd.)

Am29823A

	Inputs OE CLR EN D1 CP				Internal	Outputs	
ŌĒ	CLR	EN	Dį	СР	kā.	Υı	Function
H	H	L	L H	† †	T L	Z Z	Hi-Z
H	т.	X	X	X	H H	Z L	Clear
ΗL	HH	II	X	X	NC NC	Z NC	Hold
HHLL	IIII	ب ب ب ب	דוד	† † †	IJIJ	Z Z L H	Load

Am29825A

Inputs					Internal	Outputs	
OE*	CLR	EN	Di	СP	ō	Yi	Function
L	I I	۲	H	† †	H	Z Z	H⊦Z
L H	L	X	X	X	H	Z L	Clear
L	ΞΞ	H	X	X	NC NC	Z NC	Hold
LLHH			LHLH	† † †	エーエー	Z Z L H	Load

^{*}OE is an Active-HIGH internal signal produced as follows:

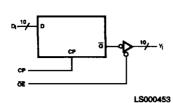
ŌE ₁	ŌE ₂	ŌĒ3	OE
Н	×	X	L
×	н	×	L
X	×	Н	L
L	L	L	н

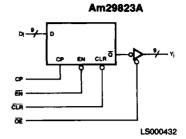
H = HIGH L = LOW X = Don't Care

NC = No Change † = LOW-to-HIGH Transition Z = High Impedance

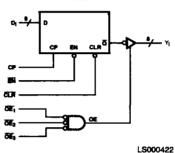
LOGIC SYMBOLS

Am29821A





Am29825A



FUNCTION TABLES

Am29821A

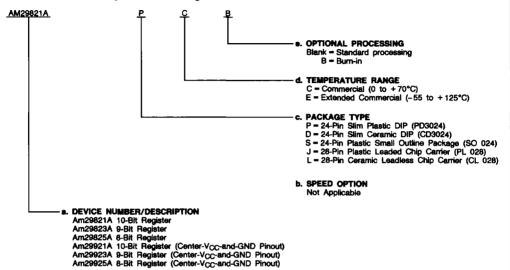
ı	nput	•	Internal	ernal Outputs	
ŌĒ	Ďį	CP	ā _i	Yį	Function
H	HF	Ť	H	Z Z	Hi-Z
اد	H	† †	H	L H	Load

H = HIGH L = LOW 1 = LOW-to-HIGH Transition Z = High Impedance

ORDERING INFORMATION Standard Products

AMD products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Package Type
- d. Temperature Range
- e. Optional Processing



Valid Co	mbinations
AM29821A	20 202 20 202
AM29823A	PC, PCB, DC, DCB, DE, SC, JC, LC
AM29825A	24, 24, 36, 23
AM29921A	
AM29923A	PC, PCB, DC, DCB, DE
AM29925A	

Valid Combinations

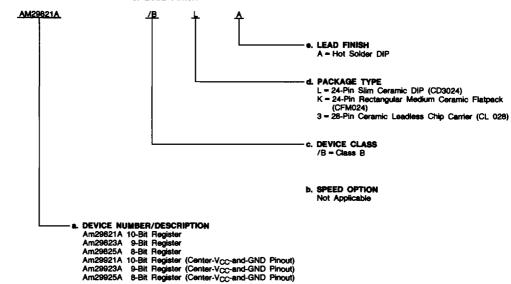
Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released valid combinations, and to obtain additional data on AMD's standard military grade products.

ORDERING INFORMATION (Cont'd.)

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Device Class
- d. Package Type
- e. Lead Finish



Valid Cor	Valid Combinations					
AM29821A						
AM29823A	/BLA, /BKA, /B3A					
AM29825A						
AM29921A						
AM29923A	/BLA					
AM29925A						

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

PIN DESCRIPTION

- Di Data Input (Input)
 - Di are the register data inputs.
- Yi Data Outputs (Output)
- Yi are the three-state data outputs.
- CP Clock Pulse (Input, LOW-to-HIGH Transition)
 Clock Pulse is the clock input for the registers. Data is
 entered into the registers on LOW-to-HIGH transitions.

Am29821A Only

OE Output Enable (Input, Active LOW)

When the \overline{OE} input is HIGH, the Y_i outputs are in the high-impedance state. When \overline{OE} is LOW, the register data is transferred to the Y_i outputs.

Am29823A Only

EN Clock Enable (Input, Active LOW)

When the \overline{EN} input is LOW, data on the D_i inputs are transferred to the $\overline{Q_i}$ outputs on the LOW-to-HIGH clock transition. When \overline{EN} is HIGH, the $\overline{Q_i}$ outputs do not change state, regardless of data or clock input transitions.

CLR Clear (Input, Active LOW)

When CLR is LOW, the internal register is cleared. When CLR is LOW and OE is LOW, the Y_i outputs are LOW. When CLR is HIGH, data can be entered into the register.

OE Output Enable (Input, Active LOW)

When the \overline{OE} input is HIGH, the Y_i outputs are put in the high-impedance state. When \overline{OE} is LOW, the register data is passed to the Y_i outputs.

Am29825A Only

EN Clock Enable (Input, Active LOW)

When the \overline{EN} input is LOW, data on the D_i inputs are transferred to the $\overline{Q_i}$ outputs on the LOW-to-HIGH clock transition. When \overline{EN} is HIGH, the $\overline{Q_i}$ outputs do not change state, regardless of data or clock input transitions.

CLR Clear (Input, Active LOW)

When CLR is LOW, the internal register is cleared. When CLR is LOW and all OE; are LOW, the Y; outputs are LOW. When CLR is HIGH, data can be entered into the register.

OE Output Enables (Input, Active LOW)

When \overline{OE}_1 , \overline{OE}_2 , and \overline{OE}_3 are all LOW, register data is passed to the Y₁ outputs. If any or all \overline{OE}_i are HIGH, the Y₁ outputs are put in a high-impedance state.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature65 to +150°C
Ambient Temperature with
Power Applied55 to +125°C
Supply Voltage to Ground Potential
Continuous0.5 V to +7.0 V
DC Voltage Applied to Outputs
for High Output State0.5 V to 5.5 V
DC Input Voltage1.5 V to +6.0 V
DC Output Current, into Outputs 100 mA
DC Input Current30 mA to +5.0 mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices	
Temperature (T _A)	0 to +70°C
Supply Voltage (VCC)	+4.5 V to +5.5 V
Military (M) and Extended Commerc	ial (E) Devices
Temperature (T _C)	55 to +125°C
Supply Voltage (V _{CC})	, +4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

DC CHARACTERISTICS over operating range unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Parameter Symbol	Parameter Description	Test	Conditions	Min.	Max.	Units	
		V _{CC} = 4.5 V	I _{OH} = -15 mA	2.4			
VOH	Output HIGH Voltage	VIN = VIH or VIL	IOH = -24 mA	2.0		Volts	
	Output LOW Voltage	V _{CC} = 4.5 V	MIL, IOL = 32 mA		0.5	Volts	
V _{OL}	Output LOW Voltage	VIN = VIH or VIL	COM'L, IOL = 48 mA		0.5	VORS	
V _{IH}	Input HIGH Voltage	Guaranteed Input Logical Voltage for All Inputs (No		2.0		Volts	
VIL	Input LOW Voltage	Guaranteed Input Logical Voltage for All Inputs (No			0.8	Volts	
VI	Input Clamp Voltage	V _{CC} = 4.5 V, I _{IN} = -18 m	ıA		- 1.2	Volts	
ابر	Input LOW Current	V _{CC} = 5.5 V, V _{IN} = 0.4 V			-500	μΑ	
l _{iH}	Input HIGH Current	V _{CC} = 5.5 V, V _{IN} = 2.7 V			50	μА	
l _l	Input HIGH Current	V _{CC} = 5.5 V, V _{IN} = 5.5 V			100	μΑ	
lozL	Output Off-State Current (High Impedance)		V _O = 0.4 V		-50		
lozh		V _{CC} = 5.5 V	V _O = 2.7 V		50	μA	
lsc .	Output Short-Circuit Current	V _{CC} = 5.5 V, V _{OUT} = 0 V (Note 2)		-75	-250	mA	
loff	Bus Leakage Current	V _{CC} = 0 V, V _{OUT} = 2.9 V			100	μΑ	
			Outputs LOW		100	mA	
		Am29821A/Am29921A	Outputs HIGH		88		
			Outputs Hi-Z	utputs Hi-Z		1	
	Supply Current		Outputs LOW		100		
lcc	(Note 3)	Am29823A/Am29823A	Outputs HIGH Outputs Hi-Z		88	mA	
					96		
		Am29825A/Am29925A	Outputs LOW		94	mA	
		Am29825A/Am29925A	Outputs HIGH		84		
			Outputs Hi-Z		92		

Notes: 1. Input thresholds are tested during DC parameter testing, and may be tested in combination with other DC parameters.

Not more than one output shorted at a time. Duration of the short-circuit test should not exceed one second.
 Clock input, CP, is HIGH after clocking in data. Parameter tested with V_{CC} = Max. and outputs unloaded.

SWITCHING CHARACTERISTICS over operating range unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted)

				COMM	ERCIAL	MILI	TARY	j
Parameter Symbol	Parameter Description		Test Conditions*	Min.	Max.	Min.	Max.	Units
t PLH	Propagation Delay Clock to	Propagation Daley Clock to V:		3.5	8	3.5	9	ns
t PHL	(OE = LOW)	.,		3.5	10	3.5	11.5	ns
ls	Data to CP Setup Time			4		5		ns
ч	Data to CP Hold Time			2		2		ns
ts	Enable (EN L) to CP Setup Time			6		7		ns
ts	Enable (EN) to CP Se	Enable (EN _) to CP Setup Time		4		5		ns
<u></u>	Enable (EN) Hold Time		C _L = 50 pF	2		2		ns
[†] PHL	Propagation Delay, Clear to	Yį	$C_L = 50 \text{ pF}^-$ $R_1 = 500 \Omega$ $R_2 = 500 \Omega$		14		15	
†REC	Clear (CLR _) to CP Se	tup Time		6		8		ns
tpwH]	HIGH		7		8		ns
tpwL	Clock Pulse Width	LOW		7		8		กร
^t PWL	Clear Pulse Width	LOW		6		7]	กร
^t zH	A	4- 14			11		12	ns
^t ZL	Output Enable Time OE L	_ 10 Y;			12		13	ns
Чz					8		9	กร
١uz	Output Disable Time OE	to Y;		1	8		9	ns

^{*}See Test Circuit and Waveforms.